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| Notice of References Cited | Application/Control No. 10/784,507 | Applicant(s)/Patent Under Reexamination ROSENBLUM, KEN | |
| | Examiner Thien T. Mai | Art Unit 2876 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------|----------------|
| | A | US-6,892,941 | 05-2005 | Rosenblum, Ken | 235/383 |
| | B | US-6,529,801 | 03-2003 | Rosenblum, Ken | 700/237 |
| | C | US-6,697,704 | 02-2004 | Rosenblum, Ken | 700/232 |
| | D | US-6,766,218 | 07-2004 | Rosenblum, Ken | 700/235 |
| | E | US-6,125,844 | 10-2000 | Samiotes, Nicholas G. | 128/200.23 |
| | F | US-6,249,717 | 06-2001 | Nicholson et al. | 700/241 |
| | G | US-6,283,322 | 09-2001 | Liff et al. | 221/7 |
| | H | US-4,918,604 | 04-1990 | Baum, Mark S. | 221/5 |
| | I | US-4,891,502 | 01-1990 | Motoi et al. | 235/379 |
| | J | US-6,152,364 | 11-2000 | Schoonen et al. | 235/375 |
| | K | US-5,945,651 | 08-1999 | Chorosinski et al. | 235/381 |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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